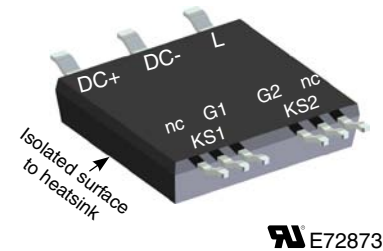
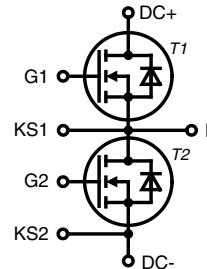


CoolMOS™ 1) Power MOSFET

ISOPLUS™ - electrically isolated surface to heatsink
Surface Mount Power Device

$$\begin{aligned} I_{D25} &= 50 \text{ A} \\ V_{DSS} &= 600 \text{ V} \\ R_{DS(on) \text{ max}} &= 45 \text{ m}\Omega \end{aligned}$$



MOSFETs T1, T2					
Symbol	Conditions	Maximum Ratings			
V_{DSS}	$T_{VJ} = 25^{\circ}\text{C}$ to 150°C	600		V	
V_{GS}		± 20		V	
I_{D25}	$T_C = 25^{\circ}\text{C}$	50		A	
I_{D80}	$T_C = 80^{\circ}\text{C}$	38		A	
E_{AS} E_{AR}	single pulse repetitive	1950 3		mJ mJ	
dV/dt	MOSFET dV/dt ruggedness $V_{DS} = 0 \dots 480 \text{ V}$	50		V/ns	
Symbol		Characteristic Values			
		$(T_{VJ} = 25^{\circ}\text{C}, \text{ unless otherwise specified})$			
	Conditions	min.	typ.	max.	
$R_{DS(on)}$	$I_D = 44 \text{ A}; V_{GS} = 10 \text{ V}$		40	45	m Ω
$V_{GS(th)}$	$I_D = 3 \text{ mA}; V_{DS} = V_{GS}$	2.5	3	3.5	V
I_{DSS}	$V_{DS} = V_{DSS}; V_{GS} = 0 \text{ V};$ $T_{VJ} = 25^{\circ}\text{C}$ $T_{VJ} = 125^{\circ}\text{C}$		50	10	μA μA
I_{GSS}	$V_{DS} = 0 \text{ V}; V_{GS} = \pm 20 \text{ V}$			100	nA
C_{iss} C_{oss}	$V_{GS} = 0 \text{ V}; V_{DS} = 100 \text{ V}; f = 1 \text{ MHz}$		6800 320		pF pF
Q_g Q_{gs} Q_{gd}	$V_{DS} = 400 \text{ V}; I_D = 44 \text{ A}$ $V_{GS} = 10 \text{ V}; R_G = 3.3 \Omega$		150 35 50	190	nC nC nC
$t_{d(on)}$ t_r $t_{d(off)}$ t_f E_{on} E_{off}	Resistive switching $T_{VJ} = 125^{\circ}\text{C}$ $V_{DS} = 380 \text{ V}; I_D = 30 \text{ A}$ $V_{GS} = 10 \text{ V}; R_G = 3.3 \Omega$		22 10 120 12 70 22		ns ns ns ns μJ μJ
$t_{d(on)}$ t_r $t_{d(off)}$ t_f E_{on} E_{off} $E_{rec(off)}$	Inductive switching $T_{VJ} = 25^{\circ}\text{C}$ $V_{DS} = 380 \text{ V}; I_D = 30 \text{ A}$ $V_{GS} = 10 \text{ V}; R_G = 330 \Omega$		900 400 520 18 5.2 0.18		ns ns ns ns mJ mJ mJ
R_{thJC} R_{thJH}	with heatsink compound; IXYS test setup		0.6	0.4	K/W K/W

Features

- **Fast CoolMOS™ 1)** power MOSFET 4th generation
 - high blocking capability
 - lowest resistance
 - avalanche rated for unclamped inductive switching (UIS)
 - low thermal resistance due to reduced chip thickness
- **Package**
 - isolated surface to heatsink
 - low coupling capacity between pins and heatsink
 - PCB space saving
 - enlarged creepage towards heatsink
 - application friendly pinout
 - low inductive current path
 - high reliability

Applications

- Switch mode power supplies (SMPS)
- Soft switching topologie
- Resonant converter

¹⁾ CoolMOS™ is a trademark of Infineon Technologies AG.

Source-Drain Diodes of T1/T2

Symbol	Conditions	Maximum Ratings				
I _{S25}	T _C = 25°C			50	A	
I _{S80}	T _C = 80°C			38	A	
Symbol	Conditions	Characteristic Values				
(T _{VJ} = 25°C, unless otherwise specified)						
			min.	typ.	max.	
V _{SD}	I _F = 44 A; V _{GS} = 0 V			0.95	1.25	V
t _{rr}	I _F = 44 A; -di _F /dt = 100 A/μs; V _R = 400 V			600		ns
Q _{RM}				17		μC
I _{RM}				60		A

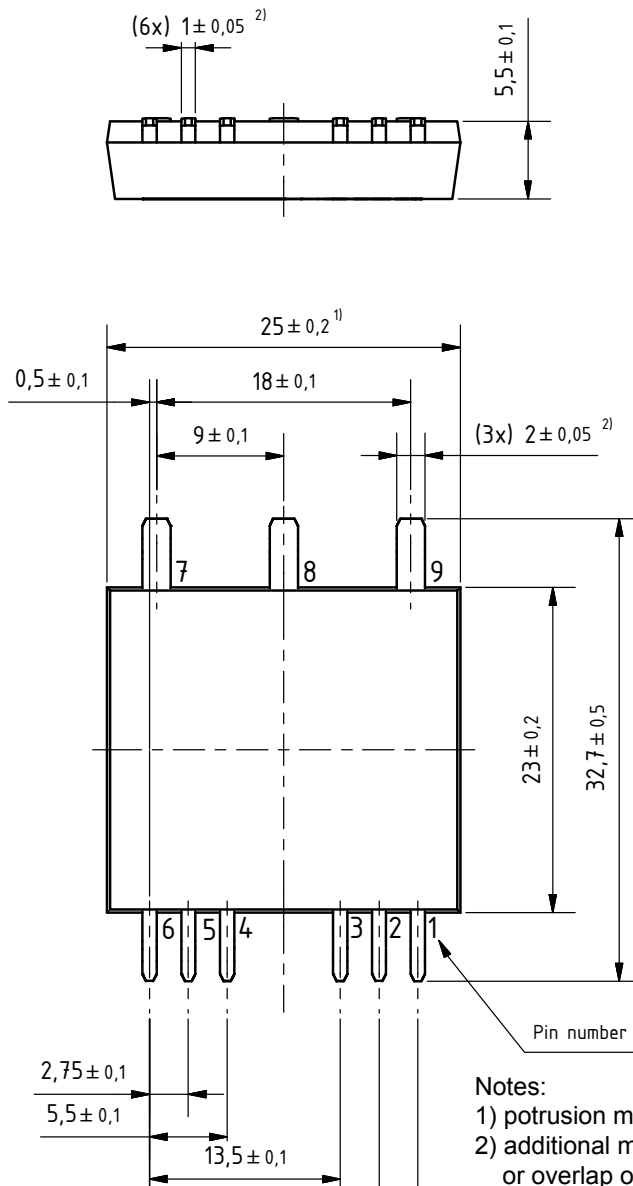
Component

Symbol	Conditions	Maximum Ratings			
T_{VJ}			-55...+150		°C
T_{stg}			-55...+125		°C
V_{ISOL}	$I_{ISOL} \leq 1\text{ mA}; 50/60\text{ Hz}$		2500		V~
F_C	mounting force		40 ... 130		N
Symbol	Conditions	Characteristic Values			
		min.	typ.	max.	
C_P	coupling capacity between shorted pins and backside metal		90		pF
d_S, d_A	pin - pin	1.65			mm
d_S, d_A	pin - backside metal	4			mm
CTI		400			
Weight			8		g

Ordering	Part Name	Marking on Product	Delivering Mode	Base Qty	Ordering Code
Standard	MKE38P600LB-TRR	MKE38P600LB	Tape&Reel	200	510486
	MKE38P600LB	MKE38P600LB	Blister	45	480601

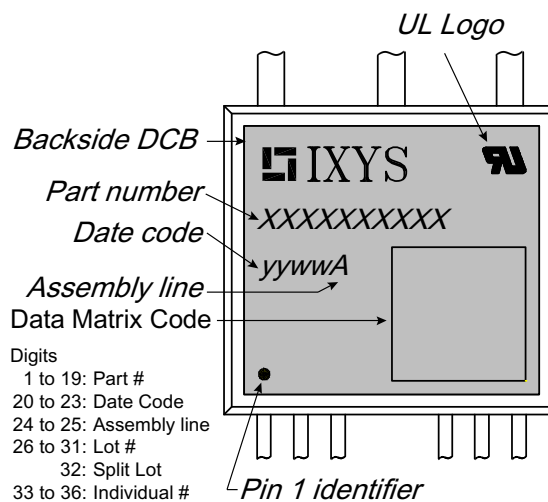
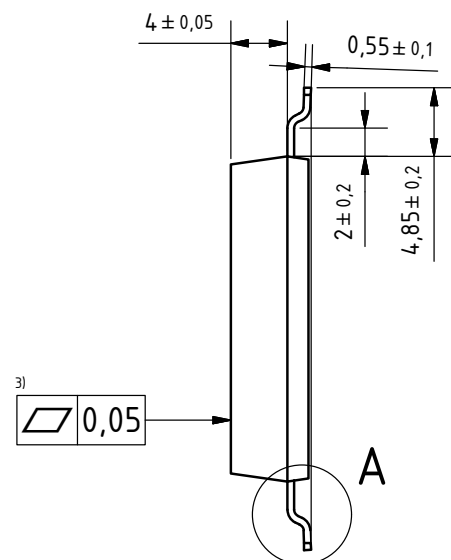
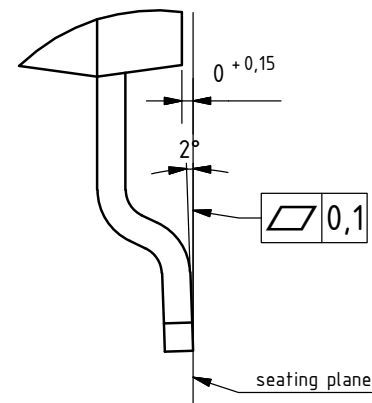
Dimensions in mm
(1 mm = 0.0394")

A (8 : 1)



Notes:

- 1) protrusion may add 0.2 mm max. on each side
- 2) additional max. 0.05 mm per side by punching misalignment or overlap of dam bar or bending compression



20130506b

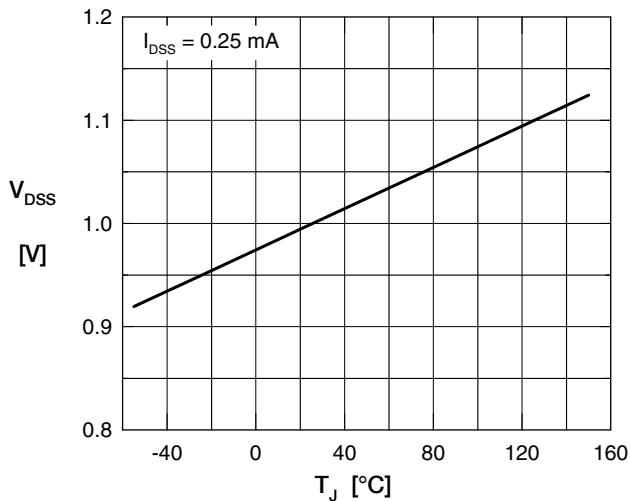


Fig.1 Drain source breakdown voltage versus temperature T_{VJ}

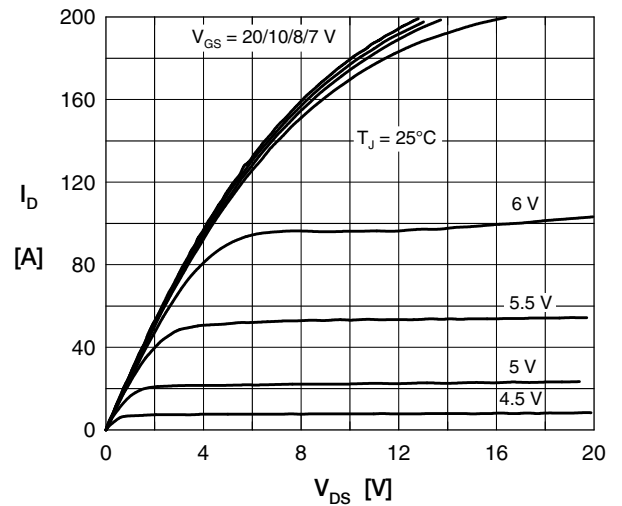


Fig. 2 Typ. output characteristics

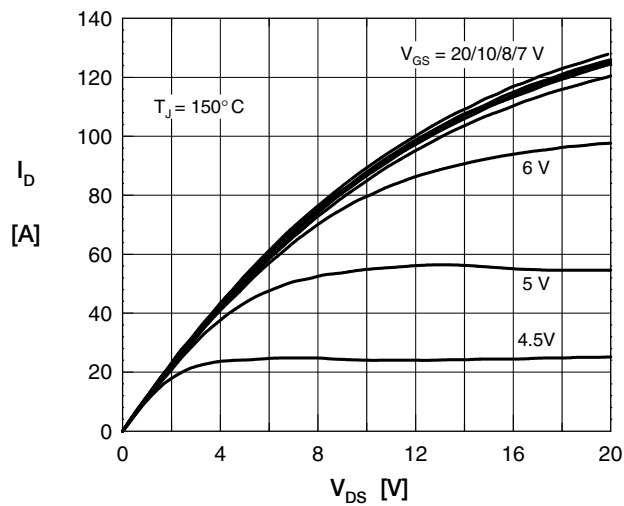


Fig. 3 Typ. output characteristics

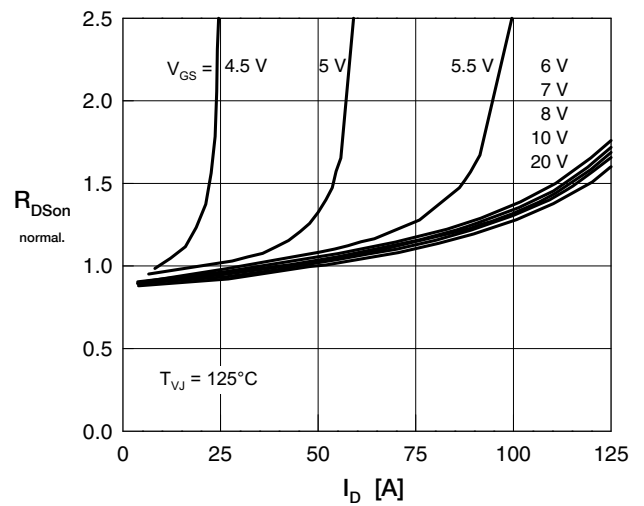


Fig. 4 Drain source on-state resistance $R_{DS(on)}$ versus I_D

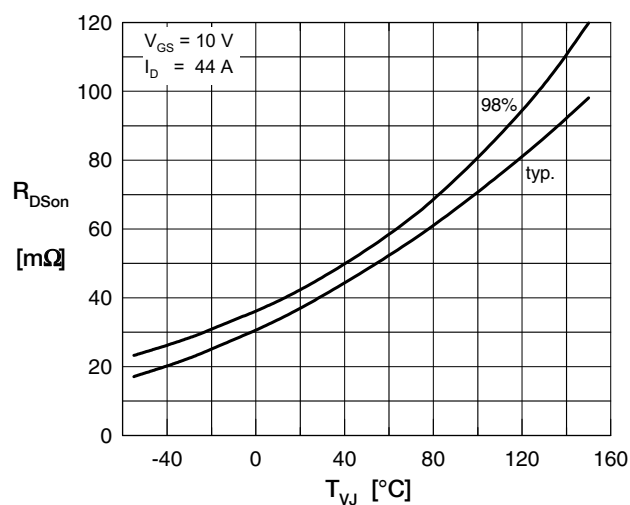


Fig.5 Drain source on-state resistance $R_{DS(on)}$ vs. junction temperature T_{VJ}

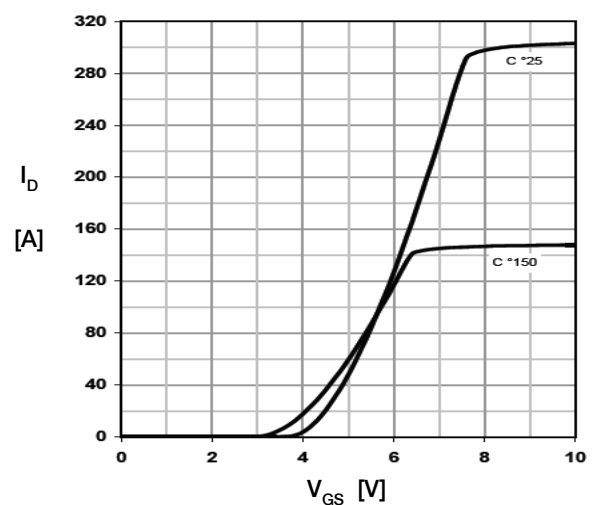
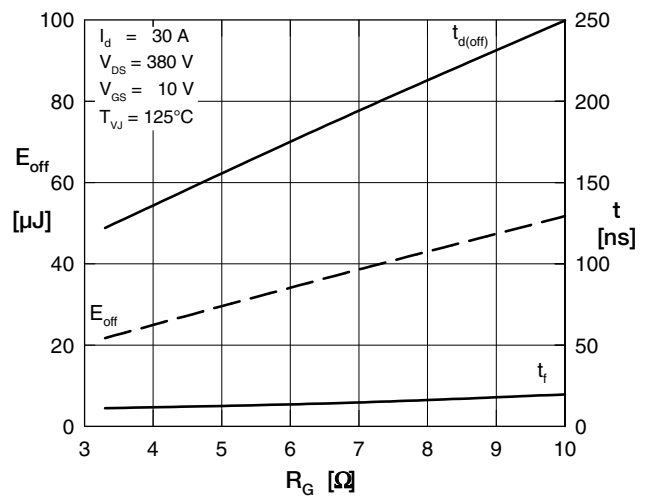
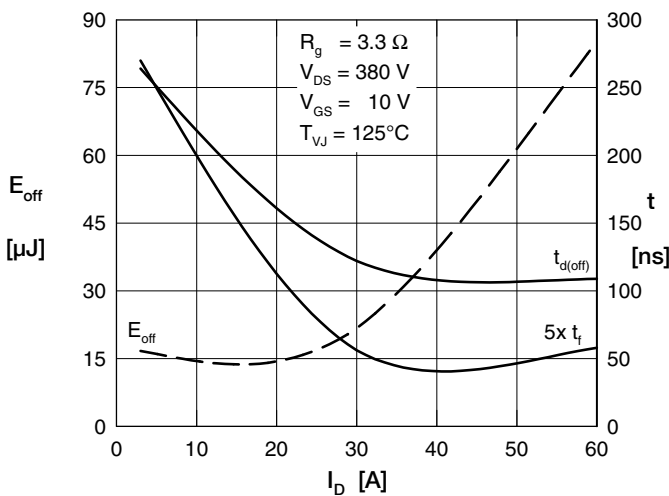
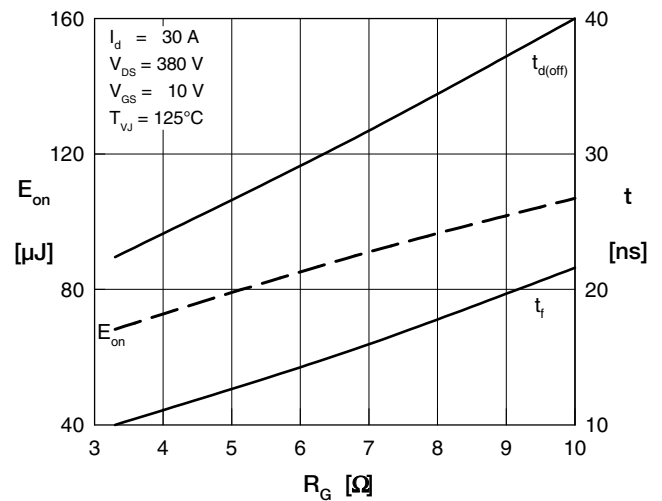
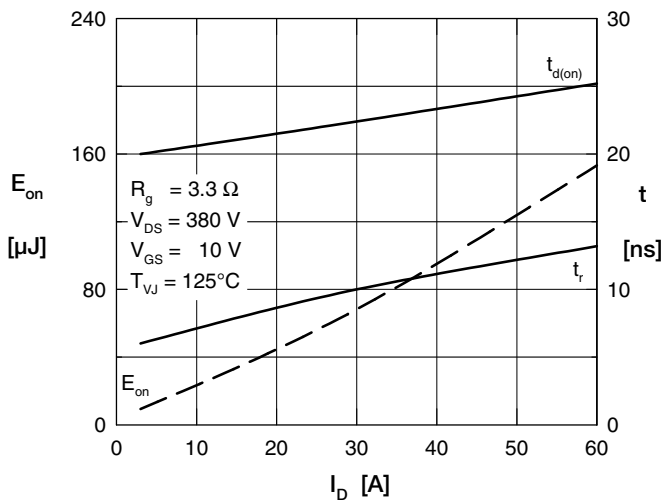
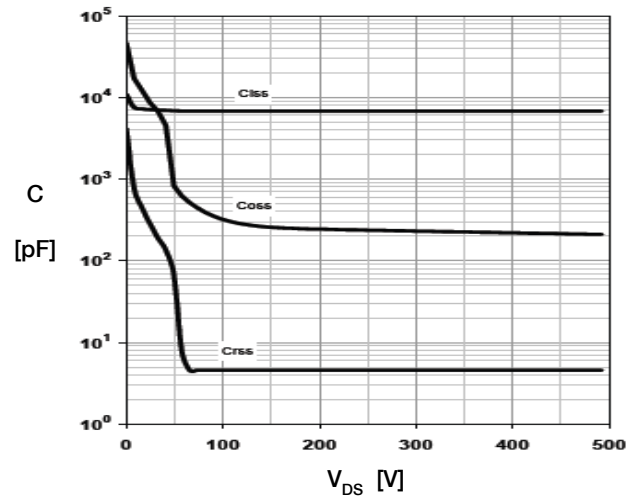
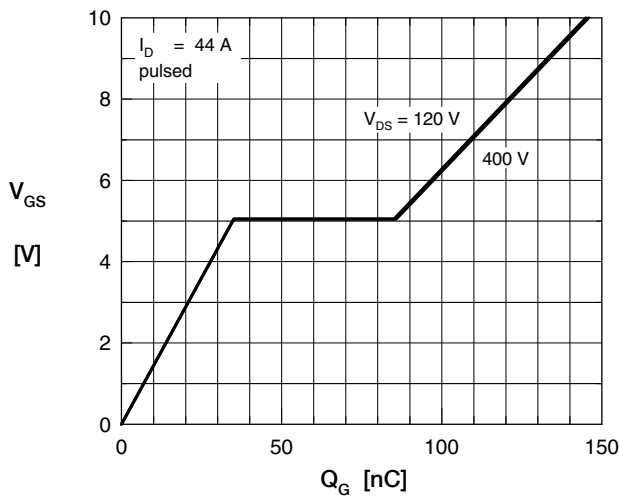


Fig.6 Typ. transfer characteristics



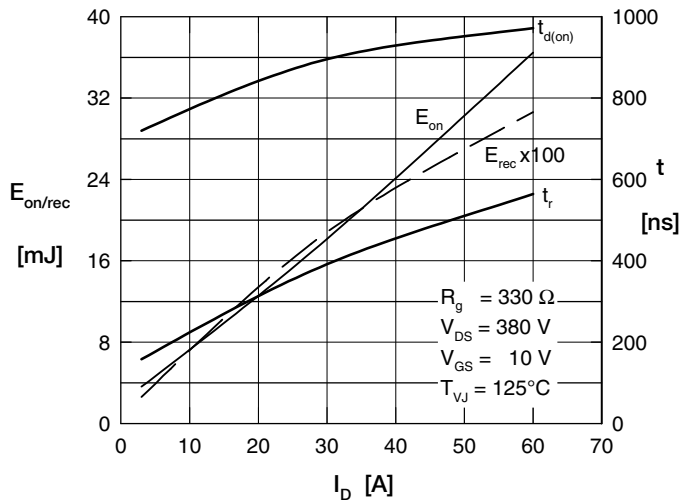


Fig. 13 Typ. turn-on energy & switching times versus collector current, inductive switching (phaseleg)

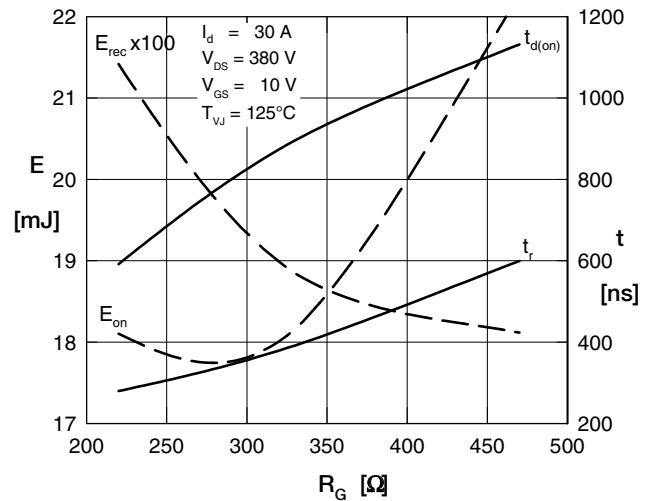


Fig. 14 Typ. turn-on energy & switching times versus gate resistor, inductive switching (phaseleg)

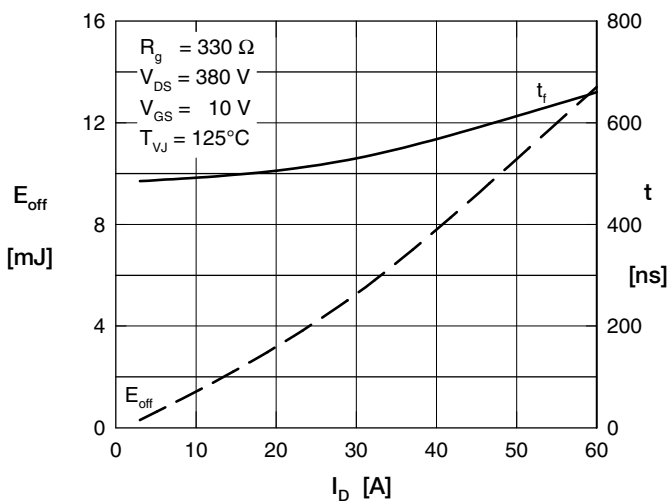


Fig. 15 Typ. turn-off energy & switching times versus collector-current, inductive switching (phaseleg)

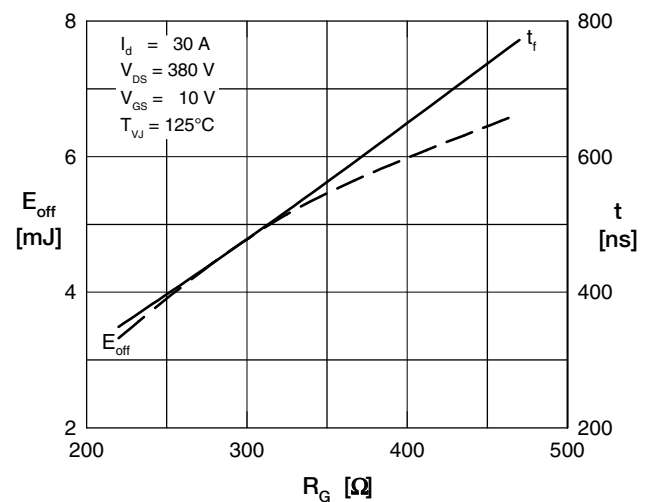


Fig. 16 Typ. turn-off energy & switching times versus gate resistor, inductive switching (phaseleg)

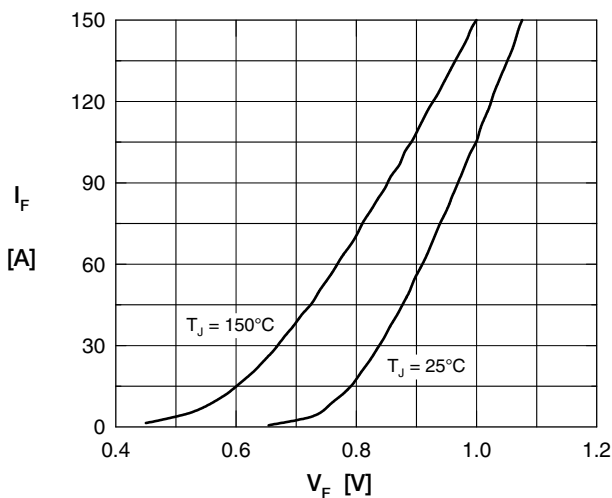


Fig. 17 Typ. forward characteristics of source drain diode D_{SD}

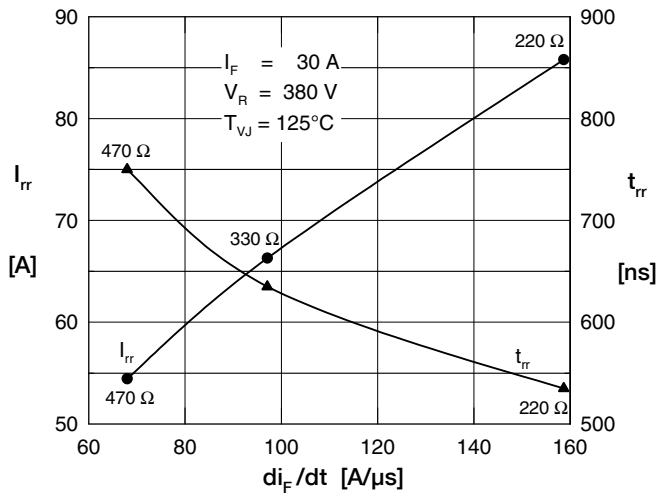


Fig. 18 Typ. reverse recovery of anti-parallel diode

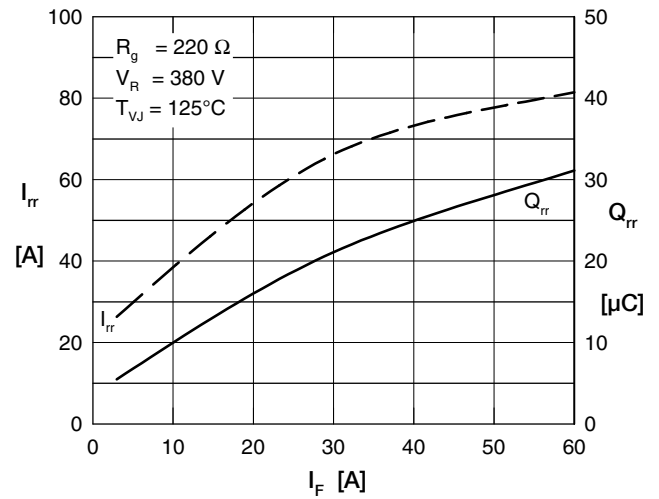


Fig. 19 Typ. reverse recovery characteristics

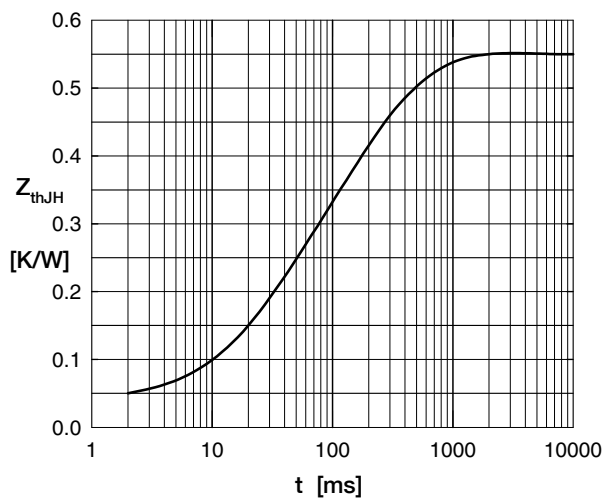


Fig. 20 Typ. transient thermal impedance of the MOSFET (IXYS test setup)